

# Sn doped $\beta$ -Ga<sub>2</sub>O<sub>3</sub> and $\beta$ -Ga<sub>2</sub>S<sub>3</sub> nanowires with red emission for solar energy spectral shifting

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Citation: *Journal of Applied Physics* **118**, 194302 (2015); doi: 10.1063/1.4935633


View online: <http://dx.doi.org/10.1063/1.4935633>

View Table of Contents: <http://aip.scitation.org/toc/jap/118/19>

Published by the *American Institute of Physics*

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Applied Physics Reviews

# Sn doped $\beta$ -Ga<sub>2</sub>O<sub>3</sub> and $\beta$ -Ga<sub>2</sub>S<sub>3</sub> nanowires with red emission for solar energy spectral shifting

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(Received 20 May 2015; accepted 1 November 2015; published online 17 November 2015)

Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> nanowires have been grown on Si(001) via the vapor–liquid–solid mechanism at 800 °C over a broad range of compositions. These have a monoclinic  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> crystal structure and minimum resistances for 1–2 at. % Sn but we observe the emergence of tetragonal rutile SnO<sub>2</sub> which dominates with increasing content of Sn. All of the nanowires exhibited photoluminescence at 2.7 eV but a red shift of the emission occurred from 2.7 eV to 1.8 eV after post growth processing under H<sub>2</sub>S above 500 °C. The red emission is related to deep donor to acceptor transitions and the formation of monoclinic  $\beta$ -Ga<sub>2</sub>S<sub>3</sub> and has been exploited for spectral shifting in a Si solar cell resulting into an increase of the power conversion efficiency from 7.2% to 8.3%.

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## I. INTRODUCTION

Metal oxide (MO) NWs such as ZnO,<sup>1</sup> SnO<sub>2</sub>,<sup>2</sup> In<sub>2</sub>O<sub>3</sub>,<sup>3</sup> Sn doped In<sub>2</sub>O<sub>3</sub>,<sup>4</sup> and Ga<sub>2</sub>O<sub>3</sub><sup>5</sup> NWs have been used extensively for the fabrication of nanoscale electronic and optoelectronic devices such as nanowire solar cells, sensors, and photodetectors. In particular, Sn doped In<sub>2</sub>O<sub>3</sub> NWs with metallic like conductivities and high transparency have been investigated in detail, while Sn doping of Ga<sub>2</sub>O<sub>3</sub> has also been considered to enable its use in devices. Tetravalent Sn is a good doping candidate for Ga<sub>2</sub>O<sub>3</sub> because it has an ionic radius of 0.69 Å which is close to that of octahedrally coordinated Ga i.e., 0.62 Å. Very recently, the resistivity of Sn doped Ga<sub>2</sub>O<sub>3</sub> epitaxial layers grown by metal organic chemical vapour deposition on Ga<sub>2</sub>O<sub>3</sub>(001) was investigated by Du *et al.*,<sup>6</sup> who found that the resistivity changed over nine orders of magnitude from 10<sup>7</sup> to 10<sup>−1</sup> Ω cm upon increasing the Sn content up to 10% and also observed a slight reduction in the energy band gap with increasing content of Sn attributed to the narrower band gap of SnO<sub>2</sub>. Similarly, Orita *et al.*<sup>7</sup> prepared Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> by pulsed laser deposition on glass and sapphire with a minimum resistivity of 1 Ω cm. The electrical conductivity of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> has also been controlled over three orders of magnitude by Si doping.<sup>8</sup> In addition to epitaxial layers, Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> and  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>/SnO<sub>2</sub> NWs have been grown by the vapour-liquid-solid (VLS) method at 900 °C, using Ga:Sn alloys with 98:2 and 92:8 wt. % ratios as sources, but Sn exhibits low solubility in  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> and only small amounts of 0.5 at. % Sn have been shown to be incorporated successfully thereby improving the electrical conductivity.<sup>9,10</sup>

Besides doping, the surface passivation of MO NWs is also necessary to prevent fluctuations in their conductivity

due to the adsorption and desorption of oxygen or water. This has been carried out on ZnO and SnO<sub>2</sub> NWs using polyimide and poly methyl methacrylate, respectively.<sup>11,12</sup> Sulphur passivation has been used to improve the properties of III-V NWs but not MO NWs. Recently, we investigated the sulphur passivation and conversion of SnO<sub>2</sub> into SnS<sub>2</sub> NWs,<sup>13</sup> while we have shown that the exposure of Sn doped In<sub>2</sub>O<sub>3</sub> NWs to H<sub>2</sub>S between 100 °C and 600 °C resulted in the formation of SnS<sub>2</sub>/In<sub>2</sub>O<sub>3</sub> NWs and the emergence of band edge photoluminescence (PL) emission at 3.4 eV corresponding to In<sub>2</sub>O<sub>3</sub> which was not observed in the as-grown Sn doped In<sub>2</sub>O<sub>3</sub> NWs.<sup>14</sup> Therefore, the sulphur passivation of MO NWs may be used to improve their properties but also obtain metal oxy-sulphide (MOxS) NWs with different electrical and optical properties similar to  $\beta$ -In<sub>2</sub>S<sub>3−3x</sub>O<sub>3x</sub>. The latter has an optical band gap which was found to vary from 2.1 eV in pure  $\beta$ -In<sub>2</sub>S<sub>3</sub> to 2.9 eV when it contained 8.5 at. % of oxygen and has been proposed as an alternative to CdS buffer layers in CuIn<sub>x</sub>Ga<sub>1−x</sub>Se<sub>2</sub> solar cells.<sup>15</sup> Besides, the sulphur passivation of MO NWs is also useful for their incorporation in devices where they are subjected to various liquids containing S, Na<sub>2</sub>S, e.g., in quantum dot sensitised solar cells (QDSSc). The promise and challenges of nanostructured solar cells have been recently described by Beard *et al.*<sup>16</sup> while it has been shown that the efficiency of solar cells may be improved by integrating a luminescent spectral conversion layer into the cell structure.<sup>17</sup> Evidence of spectral shifting in Si solar cells was recently shown using CuInS<sub>2</sub>/ZnS core-shell QDs with red emission,<sup>18</sup> so the conversion of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> to  $\beta$ -Ga<sub>2</sub>S<sub>3</sub> NWs with red emission may be also beneficial for improving the performance of Si solar cells.

Hence we have undertaken an investigation into (a) the growth of Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs via the VLS mechanism over a broader range of compositions than what has been

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considered previously and their structural, electrical, and optical properties and (b) the effect of post growth processing under  $\text{H}_2\text{S}$  between  $300^\circ\text{C}$  and  $900^\circ\text{C}$  and the use of the resultant  $\beta\text{-Ga}_2\text{S}_3/\text{Ga}_2\text{O}_3$  NWs for spectral shifting in a Si solar cell. We find that the Sn doped  $\beta\text{-Ga}_2\text{O}_3$  NWs with 1–2 at. % Sn exhibited broad PL with a maximum at 2.7 eV and had the smallest resistances consistent with the findings of Du *et al.*<sup>6</sup> Increasing the Sn content of the source, resulted into the formation of tetragonal rutile  $\text{SnO}_2$  and a gradual suppression of the  $\beta\text{-Ga}_2\text{O}_3$  phase, that was accompanied by a large increase in resistance but the PL did not change significantly. However, we observed a red shift of the PL from 2.7 eV to 1.8 eV upon post growth processing of the Sn doped  $\text{Ga}_2\text{O}_3$  NWs containing only 1–2 at. % Sn under  $\text{H}_2\text{S}$  between  $600^\circ\text{C}$  and  $900^\circ\text{C}$ . The red emission is directly related to the formation of monoclinic  $\beta\text{-Ga}_2\text{S}_3$  NWs and radiative transitions between deep donor to acceptor states which has not been observed previously in one dimensional  $\text{Ga}_2\text{S}_3$  NWs. This has been exploited for spectral shifting in a Si solar cell resulting into an increase of the power conversion efficiency from 7.2% to 8.3%.

## II. METHODS

Sn doped  $\text{Ga}_2\text{O}_3$  NWs were grown using a low-pressure chemical vapour deposition (LPCVD) hot wall reactor consisting of a 1 in. quartz tube, capable of reaching  $1100^\circ\text{C}$  which was fed from a manifold with four mass flow controllers connected to Ar,  $\text{O}_2$ ,  $\text{NH}_3$ , and  $\text{H}_2$ . For the growth of the Sn doped  $\text{Ga}_2\text{O}_3$  NWs, Sn (Aldrich, 2–14 Mesh, 99.9%) and Ga (Aldrich, 99.9%) were weighed with an accuracy of  $\pm 1$  mg. Square samples of  $\text{Si}(001) \approx 7\text{ mm} \times 7\text{ mm}$  were cleaned sequentially in trichloroethylene, methanol, acetone, and isopropanol, rinsed with de-ionised water, dried with nitrogen, and coated with  $\approx 1$  nm Au. Following this, 0.2 g of Sn and Ga containing 1, 4 and 10, 20, 30, 40, 50, 60, 70, 80, and 90% wt. Sn were used as a source for the growth of the Sn doped  $\text{Ga}_2\text{O}_3$  NWs and the 1 nm Au/Si(001) substrates were loaded in a boat which was positioned at the centre of the 1 in. tube. The latter was pumped down to  $10^{-4}$  mbar and subsequently purged with 600 sccms of Ar for 10 min at  $10^{-1}$  mbar, after which the temperature was increased up to  $800^\circ\text{C}$  using a ramp rate of  $30^\circ\text{C}/\text{min}$  while maintaining the same flow of Ar. Upon reaching  $800^\circ\text{C}$ , a small flow of 10 sccms  $\text{O}_2$  was added to the main flow of Ar in order to grow the Sn doped  $\text{Ga}_2\text{O}_3$  NWs over 60 min, followed by cool down over 30 min without  $\text{O}_2$ . The morphology of the Sn doped  $\text{Ga}_2\text{O}_3$  NWs was determined by scanning electron microscopy (SEM) while their crystal structure was determined by x-ray diffraction (XRD) using a Rigaku Miniflex. In addition, the Sn and Ga content were determined by energy dispersive X-ray analysis (EDX) using a Si detector with resolution of 100 eV and accelerating voltage of 20 kV. The actual % at. content of Sn and Ga in the Sn doped  $\text{Ga}_2\text{O}_3$  NWs determined by EDX should not be confused with the % wt. of Ga or Sn used on the upstream side as a source for the growth of the Sn doped  $\beta\text{-Ga}_2\text{O}_3$  NWs.

Steady state absorption-transmission spectra of the Sn doped  $\text{Ga}_2\text{O}_3$  NWs, grown on fused silica for 10 min in order

to maintain transparency, were obtained with a Perkin-Elmer UV-Vis spectrophotometer while the PL of the Sn doped  $\text{Ga}_2\text{O}_3$  NWs on Si(001) was measured between 10 and 300 K using an excitation wavelength of 266 nm. The resistance of the Sn doped  $\text{Ga}_2\text{O}_3$  NW networks that were grown on  $5\text{ mm} \times 10\text{ mm}$  fused silica for the purpose of applying large voltages were measured in a two terminal configuration similar to Ho and Chen<sup>19</sup> using Ag contacts. Furthermore, the Sn doped  $\text{Ga}_2\text{O}_3$  NWs were exposed to 50 sccm  $\text{H}_2\text{S}$  between  $300^\circ\text{C}$  and  $900^\circ\text{C}$  for 60 min using a ramp rate of  $10^\circ\text{C}/\text{min}$  in a different hot wall reactor capable of reaching  $1500^\circ\text{C}$  and their morphology was inspected again by SEM while changes in their crystal structure were determined by XRD and the steady state absorption—transmission and PL were measured again between 10 and 300 K. Finally, the resultant  $\beta\text{-Ga}_2\text{S}_3/\text{Ga}_2\text{O}_3$  NWs were deposited on the front surface of a Si solar cell which was fabricated by Al induced crystallization of an amorphous layer of Si resulting into simultaneous p-type doping, details of which are described elsewhere<sup>20</sup> and the I V characteristics were obtained in the dark but also under light.

## III. RESULTS AND DISCUSSION

We have shown previously that the reaction of Ga with  $\text{O}_2$  at  $900^\circ\text{C}$  and 1 atm lead to the growth of  $\beta\text{-Ga}_2\text{O}_3$  NWs on 1 nm Au/Si(001) with lengths up to  $\approx 100\text{ }\mu\text{m}$  and diameters of  $\approx 50\text{ nm}$  but the yield and uniformity over areas greater than  $10\text{ mm} \times 10\text{ mm}$  was not satisfactory. The  $\beta\text{-Ga}_2\text{O}_3$  NWs had a monoclinic  $\beta\text{-Ga}_2\text{O}_3$  crystal structure with lattice constants of  $a = 12.23\text{ }\text{\AA}$ ,  $b = 3.04\text{ }\text{\AA}$ ,  $c = 5.80\text{ }\text{\AA}$ , and  $\beta = 103.7^\circ$  belonging to the  $C_{2h}^3 C 2/m$  space group. The  $\beta\text{-Ga}_2\text{O}_3$  NWs exhibited PL with a maximum at 520 nm or 2.4 eV, related to oxygen vacancies and states lying energetically in the upper half of the energy band gap of  $\beta\text{-Ga}_2\text{O}_3$  as shown by ultrafast absorption-transmission spectroscopy.<sup>21</sup> Interestingly, these  $\beta\text{-Ga}_2\text{O}_3$  NWs were fully converted into GaN NWs with a hexagonal wurtzite crystal structure under 250 sccm of  $\text{NH}_3$  between  $900^\circ\text{C}$  and  $1000^\circ\text{C}$ , which also resulted into a gradual suppression and shift of the PL from 2.4 eV to 3.4 eV, corresponding to band edge emission from the GaN NWs.<sup>22</sup> We did not observe any residual or side emission at 520 nm or 2.4 eV left over from the original  $\beta\text{-Ga}_2\text{O}_3$  NWs. Similar to the growth of  $\beta\text{-Ga}_2\text{O}_3$  NWs, we have found that  $\text{In}_2\text{O}_3$  NWs with lengths up to  $\approx 1\text{ }\mu\text{m}$  and diameters of  $\approx 50\text{ nm}$  could be obtained on 1 nm Au/Si(001) at  $700^\circ\text{C}$  and 1 atm via the reaction of In and  $\text{O}_2$  (Ref. 23) but the yield and uniformity was also limited to  $\approx 10\text{ mm} \times 10\text{ mm}$ . In contrast, a significantly higher yield and uniform distribution of Sn doped  $\text{In}_2\text{O}_3$  NWs with lengths up to  $\approx 100\text{ }\mu\text{m}$  and diameters of  $\approx 50\text{ nm}$  were obtained by LPCVD on 1 nm Au/Si(001) over areas greater than  $10\text{ mm} \times 10\text{ mm}$  up to  $\approx 100\text{ mm}$  away from the source of Sn and In at  $800^\circ\text{C}$  and 1 mbar.<sup>4</sup> This is a direct consequence of the large vapor pressure of In and Sn at  $10^{-1}$  mbar and  $800^\circ\text{C}$ . The Sn doped  $\text{In}_2\text{O}_3$  NWs grown via the VLS mechanism have a cubic bixbyite crystal structure, metallic like conductivities and exhibited PL at 2.4 eV while post growth processing under  $\text{H}_2\text{S}$  up to  $400^\circ\text{C}$  resulted into



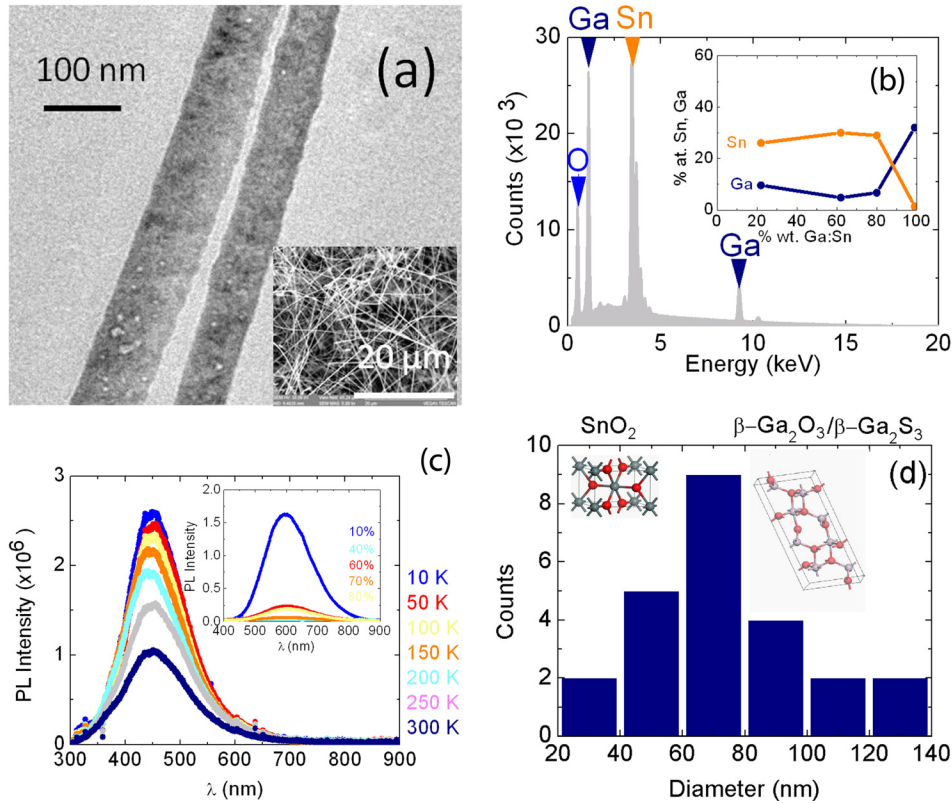


FIG. 1. (a) TEM image of the Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs grown on 1 nm Au/Si(001) at 800 °C and 1 mbar with  $\approx 1$  at. % Sn; inset shows SEM image of Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NW network (b) typical EDX spectrum of SnO<sub>2</sub>/ $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs containing  $\approx 25 \pm 3$  at. % Sn; inset shows variation of the at. % Sn and Ga in the Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs versus % wt. of Ga: Sn used as a source for their growth (c) temperature dependence of the PL from Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs with 1–2 at. % Sn between 10 and 300 K; inset shows the PL of the SnO<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> NWs obtained using more than 10% Sn (d) histogram of diameters; insets show the stick and ball crystal structures of SnO<sub>2</sub> and Ga<sub>2</sub>S<sub>3</sub>/Ga<sub>2</sub>O<sub>3</sub>.

the emergence of PL at 3.5 eV, which is close to band edge emission of cubic In<sub>2</sub>O<sub>3</sub>.<sup>14</sup>

Here, we have grown Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs on 1 nm Au/Si(001) using exactly the same growth conditions used for Sn doped In<sub>2</sub>O<sub>3</sub> NWs and obtained a high yield, uniform distribution of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs over large areas, greater than 10 mm  $\times$  10 mm, which is important for their growth on Si wafer solar cells. A typical SEM and TEM image is shown in Fig. 1(a) from which we find that the Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs have lengths of  $\approx 100 \mu\text{m}$  and average diameters of 70 nm as shown in Fig. 1(d). The Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs have the monoclinic crystal structure of  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> as shown by the XRD in Fig. 2, but we also detected peaks corresponding to the tetragonal rutile crystal structure of SnO<sub>2</sub> above 4% wt. Sn, which was accompanied by a gradual suppression of the monoclinic  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> crystal structure. Hence, we have the formation of two distinct phases, i.e., in essence SnO<sub>2</sub>/ $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs. Note that SnO<sub>2</sub> has a tetragonal rutile crystal structure and belongs to the P<sub>4</sub><sub>2</sub>/mm No.136 space group with lattice constants of  $a = 4.737 \text{ \AA}$  and  $c = 3.185 \text{ \AA}$ . A stick and ball model of the tetragonal rutile crystal structure as well as the monoclinic  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> is shown as an inset in Fig. 1(d). These findings are similar to the case of Sn doped In<sub>2</sub>O<sub>3</sub> NWs, where we have shown that it is possible to tune the crystal structure and composition from pure SnO<sub>2</sub> with a tetragonal rutile crystal structure to pure cubic bixbyite In<sub>2</sub>O<sub>3</sub> simply by varying the ratio of Sn to In of the metal source which also results into a mixture of two phases in between, i.e., SnO<sub>2</sub>/In<sub>2</sub>O<sub>3</sub> NWs.<sup>4</sup> A typical EDX spectrum of the SnO<sub>2</sub>/ $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs consisting of tetragonal rutile SnO<sub>2</sub> and monoclinic  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> is shown in Fig. 1(b) where one may clearly observe the peaks belonging to Sn and Ga. We

find that the  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs obtained using 1–4 wt. % Sn actually contain 1–2 at.% Sn as shown by the inset in Fig. 1(b). This is due to the limited solubility of Sn in  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> similar to that of Sn doped In<sub>2</sub>O<sub>3</sub>. All of the SnO<sub>2</sub>/ $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs obtained using 10–80 wt. % Sn consist of 30 at. % Sn and 10 at.% Ga suggesting that the tetragonal rutile SnO<sub>2</sub> phase is dominant compared to the monoclinic

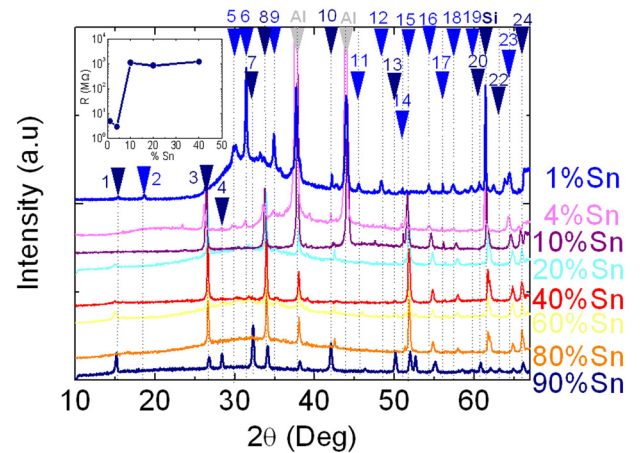


FIG. 2. XRD traces of Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs as grown on 1 nm Au/Si(001) at 800 °C and 1 mbar obtained with 1%, 4%, 10%, 20%, 40%, 60%, 80, and 90% Sn. The peaks have been labeled using arrows for clarity, in ascending order with increasing angle and correspond to 1  $\blacktriangleright$  SnO<sub>2</sub>, 2  $\blacktriangleright$   $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 3  $\blacktriangleright$  (110) SnO<sub>2</sub>, 4  $\blacktriangleright$  SnO<sub>2</sub>, 5  $\blacktriangleright$  (400)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 6  $\blacktriangleright$  (002)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 7  $\blacktriangleright$  SnO<sub>2</sub>, 8  $\blacktriangleright$  (101) SnO<sub>2</sub>, 9  $\blacktriangleright$  (111)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 10  $\blacktriangleright$  (-112)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 11  $\blacktriangleright$  (110)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 12  $\blacktriangleright$   $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 13  $\blacktriangleright$  (402)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 14  $\blacktriangleright$  (120)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 15  $\blacktriangleright$  (211) SnO<sub>2</sub>, 16  $\blacktriangleright$  (220) SnO<sub>2</sub>, 17  $\blacktriangleright$  (-113)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 18  $\blacktriangleright$  (002) SnO<sub>2</sub>, 19  $\blacktriangleright$  (113)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 20  $\blacktriangleright$  SnO<sub>2</sub>, 21  $\blacktriangleright$  Si(001), 22  $\blacktriangleright$  SnO<sub>2</sub>, 23  $\blacktriangleright$  (301) SnO<sub>2</sub>, 24  $\blacktriangleright$  SnO<sub>2</sub>; inset shows variation of resistance of the Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs at 300 K versus % wt. Sn.

$\beta$ -Ga<sub>2</sub>O<sub>3</sub>. These SnO<sub>2</sub>/ $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs exhibited broad PL with a maximum at 2.6 eV as shown as an inset in Fig. 1(c) which is similar to the PL of the  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs grown at 900 °C and 1 atm that had a maximum at 2.5 eV. Note that  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> has a direct energy gap of 4.7 eV, while SnO<sub>2</sub> has a direct energy band gap of 3.7 eV but the even-parity symmetry of the conduction-band minimum and valence-band maximum states prohibits band-edge radiative transitions. The broad PL of the SnO<sub>2</sub>/ $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs is attributed to defect states lying energetically in the upper half of the energy band gap of SnO<sub>2</sub> and Ga<sub>2</sub>O<sub>3</sub>. However, we find that the Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs containing 1–2 at. % Sn exhibited PL at 450 nm, shown in Fig. 1(c), which is slightly blue shifted. This is attributed to a suppression of the tetragonal rutile SnO<sub>2</sub> and related states similar to what we have also found in Sn doped In<sub>2</sub>O<sub>3</sub> NWs. Moreover, this is consistent with the findings of Du *et al.*<sup>6</sup> who observed a slight reduction in the optical band gap with increasing Sn content attributed to the narrower band gap of SnO<sub>2</sub> although the even-parity symmetry of the conduction-band minimum and valence-band maximum states prohibits band-edge radiative transitions in bulk SnO<sub>2</sub>.

The Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs assemblies do not have metallic like conductivities like Sn doped In<sub>2</sub>O<sub>3</sub> NWs. It is well known that  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> has n-type conductivity due to oxygen vacancies and/or Ga interstitials, but the conductivity is poor at room temperature because of its large band gap which is equal to 4.7 eV.<sup>24</sup> This has hindered its exploitation in electronic and optoelectronic devices and consequently doping is required. We have measured the resistances of the Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NW networks grown on fused silica in a two terminal configuration using Ag contacts and found that the resistances reached a minimum around 1–2 at. % Sn after which we observed a rapid increase in their resistance as shown by the inset in Fig. 2. This may be understood as follows. When the vapor pressure of Sn is small relative to that of Ga we have the formation of Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs whose resistances, initially fall with increasing content and the incorporation of Sn into the  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs, consistent with the findings of Du *et al.*<sup>6</sup> However, when the vapor pressure of Sn is larger than that of Ga it leads to the preferential formation of SnO<sub>2</sub> which have large resistances due to the small carrier density which is of the order of  $\approx 10^{16}$  cm<sup>-3</sup> as we have shown previously by THz conductivity spectroscopy.<sup>2</sup> These trends are in agreement with Du *et al.*<sup>6</sup> who found that the resistivity changed over nine orders of magnitude from  $10^7$   $\Omega$ cm to  $10^{-1}$   $\Omega$ cm upon increasing the Sn content from 0% to 10%. Evidently, the Sn content is critical and care is required to obtain Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs with reasonable conductivities and resistances for their exploitation in devices.

All of the SnO<sub>2</sub>/ $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs, containing 30 at. % Sn and 10 at. % Ga with a dominant SnO<sub>2</sub> phase were processed under H<sub>2</sub>S at 500 °C but we did not observe any monoclinic or cubic Ga<sub>2</sub>S<sub>3</sub> or hexagonal GaS in the XRD spectra shown in Fig. 3. Instead, we observed the existence of SnS<sub>2</sub>, monoclinic  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, and the tetragonal rutile crystal structure of SnO<sub>2</sub>. In other words, the SnO<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> NWs processed under H<sub>2</sub>S consist of three different phases, i.e., SnS<sub>2</sub>, SnO<sub>2</sub>, and

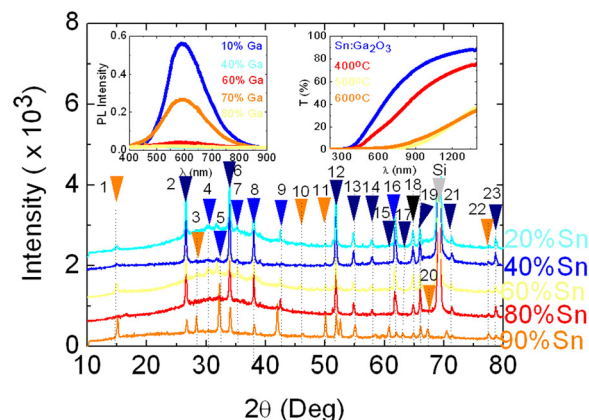


FIG. 3. XRD spectra of the Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs following post growth processing under 50 sccm of H<sub>2</sub>S at 500 °C for 60 min. The peaks are labeled in ascending order with increasing angle as follows: 1  $\blacktriangleright$  (001) SnS<sub>2</sub>, 2  $\blacktriangleright$  (110) SnO<sub>2</sub>, 3  $\blacktriangleright$  (100) SnS<sub>2</sub>, 4  $\blacktriangleright$  (400)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 5  $\blacktriangleright$  (002)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 6  $\blacktriangleright$  (101) SnO<sub>2</sub>, 7  $\blacktriangleright$  (111)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 8  $\blacktriangleright$  Al, 9  $\blacktriangleright$  (-112)  $\beta$ -Ga<sub>2</sub>O<sub>3</sub>, 10  $\blacktriangleright$  (003) SnS<sub>2</sub>, 11  $\blacktriangleright$  (110) SnS<sub>2</sub>, 12  $\blacktriangleright$  (211) SnO<sub>2</sub>, 13  $\blacktriangleright$  (220) SnO<sub>2</sub>, 14  $\blacktriangleright$  (002) SnO<sub>2</sub>, 15  $\blacktriangleright$  (310) SnO<sub>2</sub>, 16  $\blacktriangleright$  Si(001), 17  $\blacktriangleright$  (020) SnO<sub>2</sub>, 18  $\blacktriangleright$  (112) SnO<sub>2</sub>, 19  $\blacktriangleright$  (301) SnO<sub>2</sub>, 20  $\blacktriangleright$  (202) SnS<sub>2</sub>, 21  $\blacktriangleright$  (202) SnO<sub>2</sub>, 22  $\blacktriangleright$  (203) SnS<sub>2</sub>, 23  $\blacktriangleright$  (321) SnO<sub>2</sub>; left inset shows the PL of SnO<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> NWs after processing under H<sub>2</sub>S at 500 °C; right inset shows steady state transmission spectrum of the Sn doped  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> NWs with 1%–2% at Sn as-grown on fused silica before and after post growth processing under H<sub>2</sub>S at 400 °C, 500 °C, and 600 °C.

$\beta$ -Ga<sub>2</sub>O<sub>3</sub> and exhibited broad PL at  $\approx 600$  nm or 2.5 eV as shown in Fig. 3 which is more or less identical to that of the as-grown SnO<sub>2</sub>/Ga<sub>2</sub>O<sub>3</sub> NWs shown in Fig. 1. The broad PL is related to defect states in the SnO<sub>2</sub> and  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> but also possibly SnS<sub>2</sub> which is an indirect band gap semiconductor known to exhibit defect emission at  $\approx 2.0$  eV.

In contrast, the Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs, containing only 1 to 2 at. % Sn and dominant  $\beta$ -Ga<sub>2</sub>O<sub>3</sub> phase, that were processed under H<sub>2</sub>S at 700 °C–900 °C exhibited a red-shift of the PL from 2.7 eV to 1.8 eV, as shown in the inset of Fig. 4, which is directly related to the emergence of monoclinic Ga<sub>2</sub>S<sub>3</sub> as shown by the XRD traces of Fig. 4. The peaks of Ga<sub>2</sub>S<sub>3</sub> are in good agreement with those observed from layered Ga<sub>2</sub>S<sub>3</sub><sup>25</sup> but before elaborating further, we ought to mention that Ga<sub>2</sub>S<sub>3</sub> is III–VI semiconductor which can have the monoclinic, hexagonal, or cubic crystal structure. Among these, the most stable crystal structure is monoclinic of Ga<sub>2</sub>S<sub>3</sub> with lattice constants of  $\beta$ -Ga<sub>2</sub>S<sub>3</sub> are  $a = 11.11$  Å,  $b = 9.58$  Å and  $c = 6.4$  Å,  $\beta = 141.15^\circ$ . Monoclinic  $\beta$ -Ga<sub>2</sub>S<sub>3</sub> has a direct energy gap of 3.4 eV but contains many vacancies in its Ga sub lattice and consequently exhibits red emission due to deep donor to acceptor transitions related to S and Ga vacancies. Despite the fact that one third of the Ga sub-lattice sites are not occupied, Ga<sub>2</sub>S<sub>3</sub> has been investigated for light-emitting diodes and photovoltaic devices, while recently it was shown that Ga<sub>2</sub>S<sub>3</sub> has a large second-harmonic generation efficiency ideally suited for nonlinear optics.<sup>26</sup> However so far, one dimensional GaS or Ga<sub>2</sub>S<sub>3</sub> nanotubes have shown PL only between 450 and 600 nm. For instance, GaS NWs obtained by the vapor solid (VS) method exhibited PL between 550 and 600 nm while Hu *et al.*<sup>27</sup> obtained GaS NTs with PL at 450 nm. Hexagonal GaS, has a direct energy band gap of 3.05 eV and an indirect

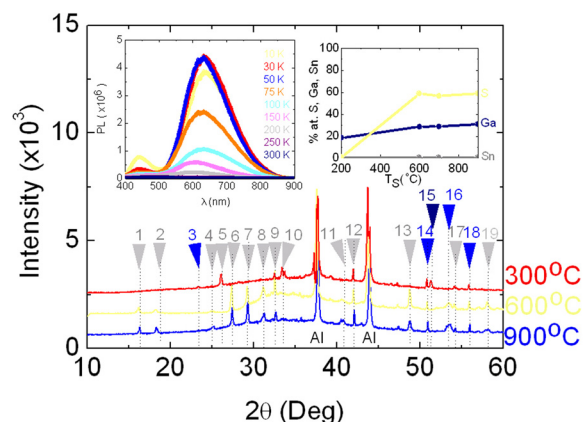


FIG. 4. XRD spectra of the Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs containing 1–2 at. % Sn that were processed under H<sub>2</sub>S at 300 °C, 600 °C, and 900 °C. The peaks are labeled for clarity, in ascending numerical order with increasing angle as follows: 1 ► (001) Ga<sub>2</sub>S<sub>3</sub>, 2 ► (−201/−110) Ga<sub>2</sub>S<sub>3</sub>, 3 ► (012) Ga<sub>2</sub>O<sub>3</sub>, 4 ► (300) Ga<sub>2</sub>S<sub>3</sub>, 5 ► (200) Ga<sub>2</sub>S<sub>3</sub>, 6 ► (−312) Ga<sub>2</sub>S<sub>3</sub>, 7 ► (101) Ga<sub>2</sub>S<sub>3</sub>, 8 ► (002) Ga<sub>2</sub>S<sub>3</sub>, 9 ► (−311) Ga<sub>2</sub>S<sub>3</sub>, 10 ► (−111) Ga<sub>2</sub>S<sub>3</sub>, 11 ► (−314) Ga<sub>2</sub>S<sub>3</sub>, 12 ► (−112) Ga<sub>2</sub>S<sub>3</sub>, 13 ► (−332) Ga<sub>2</sub>S<sub>3</sub>, 14 ► (−403) Ga<sub>2</sub>O<sub>3</sub>, 15 ► (211) SnO<sub>2</sub>, 16 ► (203) Ga<sub>2</sub>O<sub>3</sub>, 17 ► (−315/023/311) Ga<sub>2</sub>S<sub>3</sub>, 18 ► (−113) β-Ga<sub>2</sub>O<sub>3</sub>, 19 ► (311) Ga<sub>2</sub>S<sub>3</sub>. The left inset shows the PL of Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs containing 1–2 at. % between 10 and 300 K after processing under H<sub>2</sub>S at 900 °C; right inset shows the variation of % at. Sn, Ga, and S in the Sn doped β-Ga<sub>2</sub>O<sub>3</sub> NWs with small content of Sn processed under H<sub>2</sub>S between 200 °C and 900 °C.

energy gap of 2.5 eV and Sinha *et al.*<sup>28</sup> observed PL from GaS NWs at 450 nm. On the other hand, Ga<sub>2</sub>S<sub>3</sub> has an energy gap of 3.4 eV and Liu *et al.*<sup>25</sup> observed PL from layered structures of Ga<sub>2</sub>S<sub>3</sub> with a maximum around 1.6 eV, which, however, was broad and extended to 3.0 eV.

Evidently, the red emission of the Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs with 1%–2% Sn observed at 680 nm or 1.8 eV is directly related to the formation of Ga<sub>2</sub>S<sub>3</sub> not Sn and is found to persist down to 10 K, while it is also stronger than the blue emission at 2.7 eV, as shown in Fig. 4. The steady state transmission spectra through β-Ga<sub>2</sub>O<sub>3</sub> NWs, that were grown on fused silica before and after exposure to H<sub>2</sub>S at 400 °C, 500 °C, and 600 °C, are shown as an inset in Fig. 3 and suggest a decrease in the optical band gap and overall transmission coefficient consistent with the formation of β-Ga<sub>2</sub>S<sub>3</sub>. The red emission obtained from the β-Ga<sub>2</sub>O<sub>3</sub>/Ga<sub>2</sub>S<sub>3</sub> NWs could be used for the fabrication of sensors or solar cells since evidence of spectral shifting resulting into the improvement of efficiency in Si solar cells has been shown to be possible using CuInS<sub>2</sub>/ZnS core-shell quantum dots with red emission.<sup>18</sup> We have fabricated a p<sup>+</sup>n junction solar cell where the p<sup>+</sup> layer was formed by Al induced crystallization of an amorphous layer of Si, resulting into simultaneous p-type doping of the layer, details of which are described elsewhere.<sup>20</sup> The amorphous Si layer was 20 nm thick and the Al layer 10 nm thick, while the solar cell surface area was 1 cm<sup>2</sup>, as shown in Fig. 5. The bare solar cell without the β-Ga<sub>2</sub>O<sub>3</sub>/Ga<sub>2</sub>S<sub>3</sub> NWs had an open circuit voltage V<sub>OC</sub> = 0.42 V, short circuit current density J<sub>SC</sub> = 27.2 mA/cm<sup>2</sup>, and fill factor 63%, resulting in a conversion efficiency of η = 7.2%. After deposition of the β-Ga<sub>2</sub>O<sub>3</sub>/Ga<sub>2</sub>S<sub>3</sub> NWs by drop casting, the device exhibited a short circuit current J<sub>SC</sub> = 32.37 mA/cm<sup>2</sup>, V<sub>OC</sub> = 0.42 V, and fill factor of 61%,

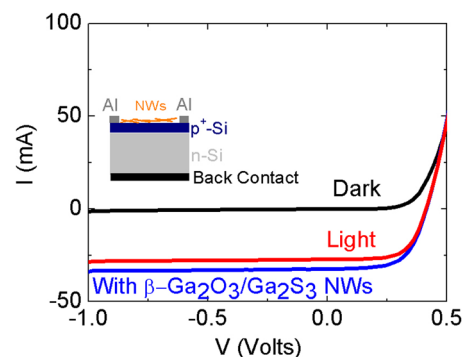


FIG. 5. I V characteristics of a Si solar cell in the dark and under one sun, before and after the transfer of β-Ga<sub>2</sub>O<sub>3</sub>/Ga<sub>2</sub>S<sub>3</sub> NWs; inset shows schematic diagram of device.

with the efficiency η increasing from 7.2% to 8.3%, which corresponds to an increase of ≈14%. This is attributed to spectral shifting and a reduction in the reflection coefficient.<sup>17</sup> Further improvements may be attained by the growth of an ordered array of Sn doped β-Ga<sub>2</sub>O<sub>3</sub> NWs on the surface of Si while the red emission of the β-Ga<sub>2</sub>O<sub>3</sub>/Ga<sub>2</sub>S<sub>3</sub> NWs could also be utilised in quantum dot sensitised solar cells.

#### IV. CONCLUSION

Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs have been grown via the VLS mechanism at 800 °C over a broad range of compositions than what has been considered previously. The Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs exhibited PL between 450 and 600 nm and had minimum resistances for 1–2 at. % Sn above which we observed the formation of SnO<sub>2</sub> which also lead to an increase in the resistance by more than three orders of magnitude. A strong red shift of the PL from 2.7 eV to 1.8 eV nm occurred after post growth processing the Sn doped Ga<sub>2</sub>O<sub>3</sub> NWs with 1–2 at. % Sn under H<sub>2</sub>S between 700 °C and 900 °C. The red emission of β-Ga<sub>2</sub>S<sub>3</sub> is due to deep donor to acceptor transitions related to S and Ga vacancies. We show that the red emission of the β-Ga<sub>2</sub>O<sub>3</sub>/β-Ga<sub>2</sub>S<sub>3</sub> NWs randomly deposited on the surface of a Si solar cell can be used for spectral shifting resulting into an increase of the power conversion efficiency from 7.2% to 8.3% corresponding to an increase of ≈14%.

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